Substitute Form PTO-1449 (Modified)			Application No. 09/379,702	
,	closure Statement	Applicant Hisashi Ohtani et al.		
(Use several si	heets if necessary)	Filing Date August 24, 1999	Group Art Unit 2815	

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA		i i				
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub- class	Transla Yes	ation No
EL	AL	JP03-289140	12/19/1991	JAPAN			Abstract	
a	AM	JP04-240733	08/28/1992	JAPAN			Abstract	
	AN							
	AO							ļ
	ΑP							<u> </u>

	Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document				
	AQ					
	AR					
	AS					
	AT					

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	Substitute Disclosure Form (PTO-1449)

	ubstitute Form PTO-1449  U.S. Department of Commerce   Patent and Trademark Office		Attorney's Docket No. 07977-093002	Application No. 09/379,702	
	***************************************	closure Statement	Applicant Hisashi Ohtani et al.		
(3	(Use several sheets if necessary) (37 CFR §1.98(b))		Filing Date August 24, 1999	Group Art Unit 2815	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
a	ΛA	5,608,232	03/04/1997	YAMAZAKI et al.			06/05/1995
a	AB	5,639,698	06/17/1997	YAMAZAKI et al.			02/15/1994
62	AC	5,851,860	12/22/1998	MAKITA et al.			06/02/1995
a	AD	5,897,347	04/27/1999	YAMAZAKI et al.			.09/24/1996
a	AE	5,956,579	09/21/1999	YAMAZAKI ct al.			07/15/1997
6	AF	6,084,247	07/04/2000	YAMAZAKI et al.			12/18/1996
w	AG	6,997,985	02/14/2006	YAMAZAKI et al.			12/18/1996
	AH						
	AI						
	AJ						
	AK						

i	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner. Initial	Desig.	Document Number	Publication Date	Country or Patent Office	Class	Sub- class	Transla Yes	tion No
Q_	AL	EP0 612 102	08/24/1994	EUROPE			In English	
a	AM	EP1 119 053	07/25/2001	EUROPE			In English	
be	AN	JP03-004564	01/10/1991	JAPAN			Abstract	
ar	AO	JP06-296020	10/21/1994	JAPAN			Abstract	
61	AP	JP07-226374	08/22/1995	JAPAN			Abstract	
a	ΛQ	JP08-031737	02/02/1996	JAPAN			Abstract	

	Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document				
	AR					
	AS					
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	AU					

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